

<b>Notice of References Cited</b>	Application/Control No. 10/591,533	Applicant(s)/Patent Under Reexamination NEGISHI ET AL.	
	Examiner David K. O'Dell	Art Unit 1625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2001210365 A (trans.)	08-2001	Japan	YAMADA et al.	H01M 10/40
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**NON-PATENT DOCUMENTS**

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	U	Xu et. al. Journal of The Electrochemical Society, 2002, 149 (5) A622-A626.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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